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Systematic error accumulation in testing GR with ET

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Overview



- ❑ Predicting systematic errors in PE: overlap signals and inaccurate waveforms
- ❑ Mock catalog for ET
- ❑ Systematic error accumulation – using parameterized post-Newtonian (PPN) coefficients tests of GR as an example

Excess strains



Where systematic errors originate (arXiv:0707.2982, 2104.01897)

- Likelihood in PE: assuming noise is stationary and Gaussian, and $d-h=n$

$$\ln L(\vec{\theta}) = -\frac{1}{2}(d-h|d-h) = -\frac{1}{2}(n|n),$$

- Maximum likelihood (ML) estimator:

$$\partial_i \ln L |_{\vec{\theta}=\vec{\theta}_{\text{ML}}} = (\partial_i h | d-h) |_{\vec{\theta}=\vec{\theta}_{\text{ML}}} = 0,$$

- The statistical error caused by noise:

$$\Delta\theta_{\text{stat}}^i \approx (\Gamma^{-1})^{ij} (\partial_j h_{\text{m}} | n)$$

$$\langle \Delta\theta_{\text{stat}}^i \rangle = 0 \quad \text{Unbiased}$$

$$\langle \Delta\theta_{\text{stat}}^i \Delta\theta_{\text{stat}}^j \rangle = (\Gamma^{-1})^{ij} \quad \text{Fisher matrix forecast}$$

- If there are strains other than noise ($d-h=n+\delta H$), the ML will be biased:

$$\Delta\theta_{\text{sys}}^i = (\Gamma^{-1})^{ij} (\partial_j h_{\text{m}} | \delta H)$$

Our concerns



$$\Delta\theta_{\text{stat}}^i \approx (\Gamma^{-1})^{ij} (\partial_j h_m | n) \quad \Delta\theta_{\text{sys}}^i = (\Gamma^{-1})^{ij} (\partial_j h_m | \delta H)$$

- **Waveform systematics:** $\delta H_{\text{waveform}} = h_{\text{real}} - h_{\text{model}}$
- **Overlap signals:**
 - **Detected overlaps:** $\delta H_{\text{do}} = h'_{\text{real}}(\theta_{\text{true}}) - h'_{\text{model}}(\theta_{\text{ML}}) \approx \Delta\theta_{\text{stat}}^i \partial_i h'_m + \delta H'_{\text{waveform}}$
 - **Undetected overlaps (SNR<8):** $\delta H_{\text{uo}} = h''_{\text{real}}(\theta_{\text{true}})$
- $\Delta\theta_{\text{stat}}^i \propto 1/\text{SNR}$, $\Delta\theta_{\text{sys}}^i$ doesn't. When SNR increases, systematic errors may dominate
- Different types of systematic errors may have impacts on each other

- Parametrized post-Newtonian (PPN) coefficient tests of GR:
 - IMRPhenomPv2 phase is characterized by a set of parameters $\{p_i\}$
 - Inspiral regime parameters: $\{\varphi_0, \dots, \varphi_7\}, \{\varphi_{5l}, \varphi_{6l}\}$
 - Phenomenological coefficients: $\{\beta_0, \dots, \beta_3\}$
 - Merger-ringdown parameters: $\{\alpha_0, \dots, \alpha_5\}$
 - $p_i \rightarrow (1 + \delta\hat{p}_i)p_i$, the $\delta\hat{p}_i$ is the testing parameter. $\delta\hat{p}_i = 0$ returns to GR
- We choose $\delta\hat{\varphi}_0$ as an example testing parameter in this work
- We perturbate $\delta\hat{\beta}_2$ as the inaccurate waveform parameter:
 - $\delta\hat{\beta}_2 = 0$: model waveform
 - $\delta\hat{\beta}_2 = 5 \times 10^{-2}$: “real” waveform for current waveform modelling, mismatch $\sim 10^{-4} - 10^{-3}$
 - $\delta\hat{\beta}_2 = 5 \times 10^{-4}$: “real” waveform for future waveform modelling, mismatch $\sim 10^{-7} - 10^{-6}$
- Parameters in GR: chirp mass, mass ratio, merger time. Other parameters are set to be perfectly known

$$\varphi_{\text{PN}}(f) = 2\pi f t_c - \varphi_c - \frac{\pi}{4} + \frac{3}{128\eta} (\pi\tilde{f})^{-5/3} \sum_{i=0}^7 [\varphi_i + \varphi_{i1} \log(\pi\tilde{f})] (\pi\tilde{f})^{i/3}.$$

Catalog simulation



- We use an analytical approximation for merger rate density (Oguri 2018)

$$\frac{R_{\text{GW}}(z)}{\text{Gpc}^{-3}\text{yr}^{-1}} = \frac{a_1 e^{a_2 z}}{e^{a_3 z} + a_4}, \quad R_{\text{GW}}^{\text{obs}}(z) = R_{\text{GW}}(z) \frac{dV_c}{dz}(z).$$

- According to local merger rate estimation, we scale a_1 to generate different merger rates: low, median, high
- BBH
 - mass: power law + peak model in GWTC-2 population inference
 - zero spin
- BNS
 - All BNS have the same intrinsic parameters
 - 1.45+1.4 solar mass, zero spin, tidal deformability parameter=425
- Isotropic inclination and sky direction
- We will test GR with all BBH events. BNS only appears as overlap background

Catalog simulation



BBH and BNS: summary
(per year)

Overlap:= $|\Delta t| < 4s$

	# of observable binaries		Detected overlaps on BBH events		Undetected overlaps on BBH events	
	BBH	BNS	# of overlaps	# (fraction) of events	# of overlaps	# (fraction) of events
Low	56526	286088	0	48380 (98%)	0	45991 (93%)
			1	937 (1.9%)	1	3217 (6.5%)
			2	11 (0.022%)	2	119 (0.24%)
					3	1 (0.0020%)
Median (with ~80000 SNR>8)	88300	1144354	0	73224 (95%)	0	58921 (77%)
			1	3574 (4.6%)	1	15658 (20%)
			2	74 (0.096%)	2	2108 (2.7%)
			3	1 (0.0010%)	3	174 (0.23%)
					4	10 (0.013%)
					5	2 (0.0030%)
High	143349	2896647	0	112745 (90%)	0	63932 (51%)
			1	11496 (9.2%)	1	42931 (34%)
			2	589 (0.47%)	2	14143 (11%)
			3	19 (0.015%)	3	3208 (2.6%)
					4	540 (0.43%)
					5	86 (0.069%)
					6	6 (0.0050%)
					7	3 (0.0020%)

Overview of systematic errors

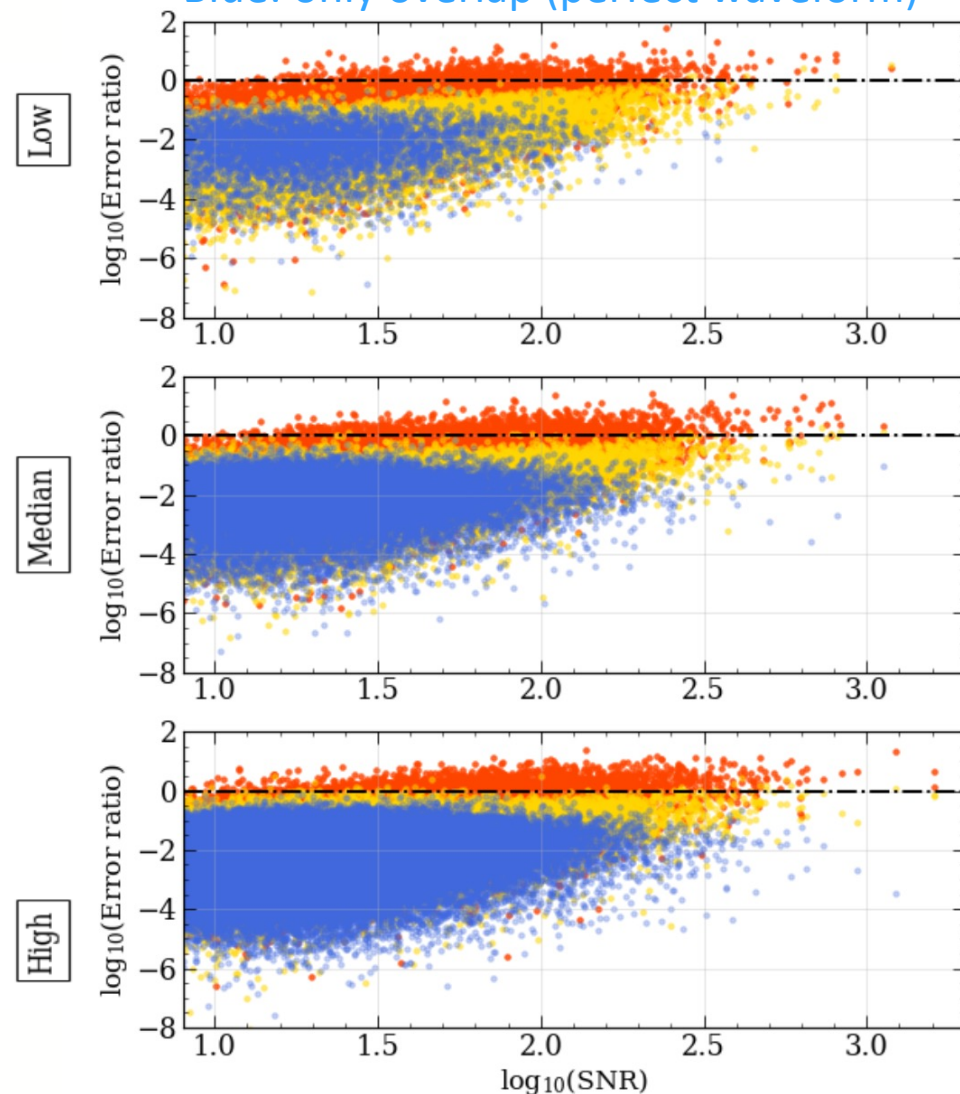


- Calculate error ratio of each event caused by different waveform models
- Error ratio increases when SNR goes higher
- Generally, systematic error < statistic error, but exceptions exist
- Statistic error decrease when combining multiple events. Could systematic error surpass statistic at some point?

Red: current waveform + overlap

Yellow: future waveform + overlap

Blue: only overlap (perfect waveform)



Catalog tests I

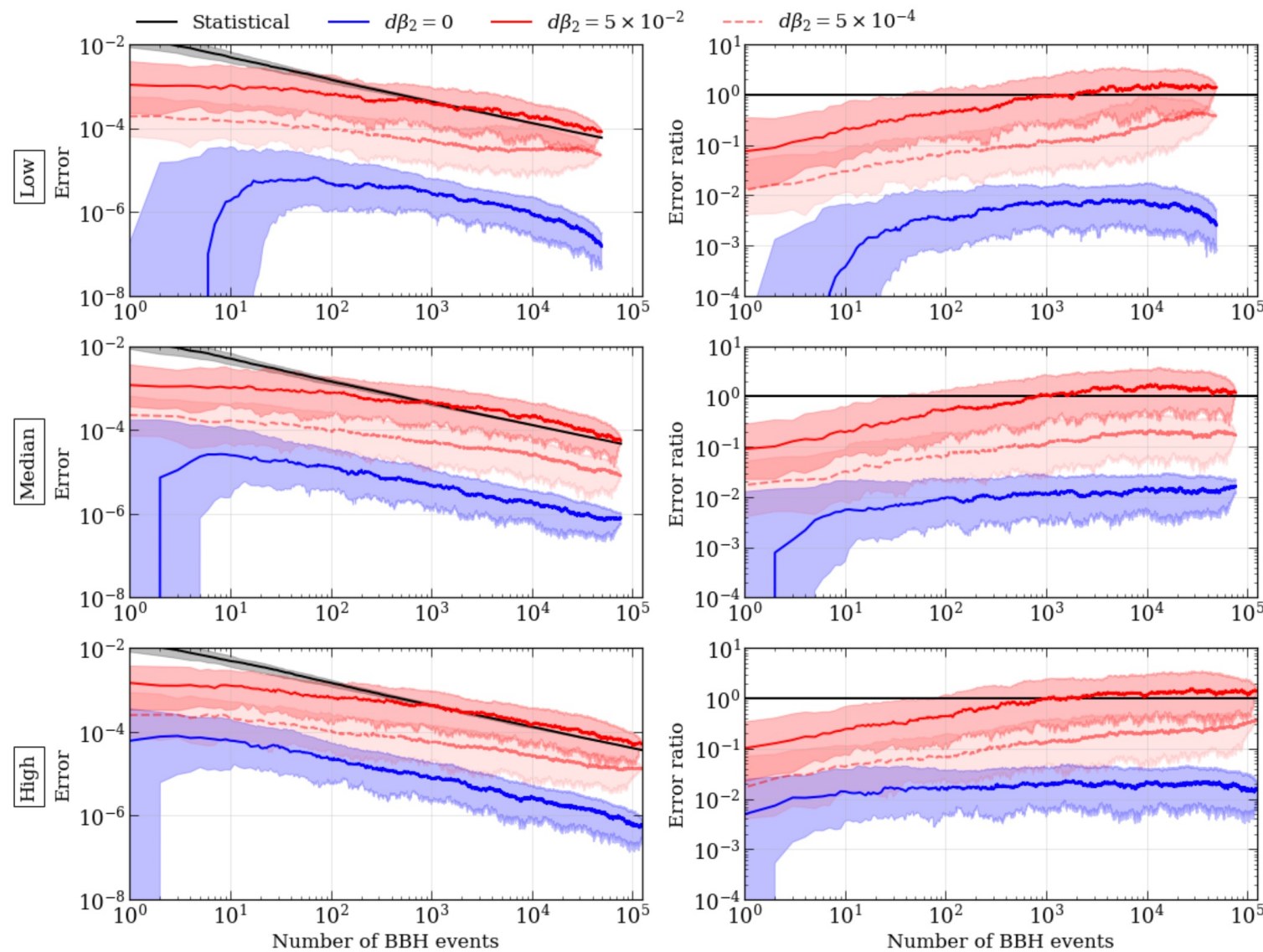


Multiplying likelihood (=posterior)

- Posterior of testing parameter is Gaussian
- Multiplying two Gaussian distributions:

$$\sigma_f^2 = \frac{\sigma_1^2 \sigma_2^2}{\sigma_1^2 + \sigma_2^2}, \quad \mu_f = \frac{\mu_1 \sigma_2^2 + \mu_2 \sigma_1^2}{\sigma_1^2 + \sigma_2^2}.$$

- Statistical error $\sim N^{(-1/2)}$
- Systematic error $\sim N^{(-1/2 + \epsilon)}$, The ϵ comes from $\mu \neq 0$ when multiplying posteriors.
- Error ratio may increase to 1 as number of events increases
- Waveform systematic is more problematic than overlap signals



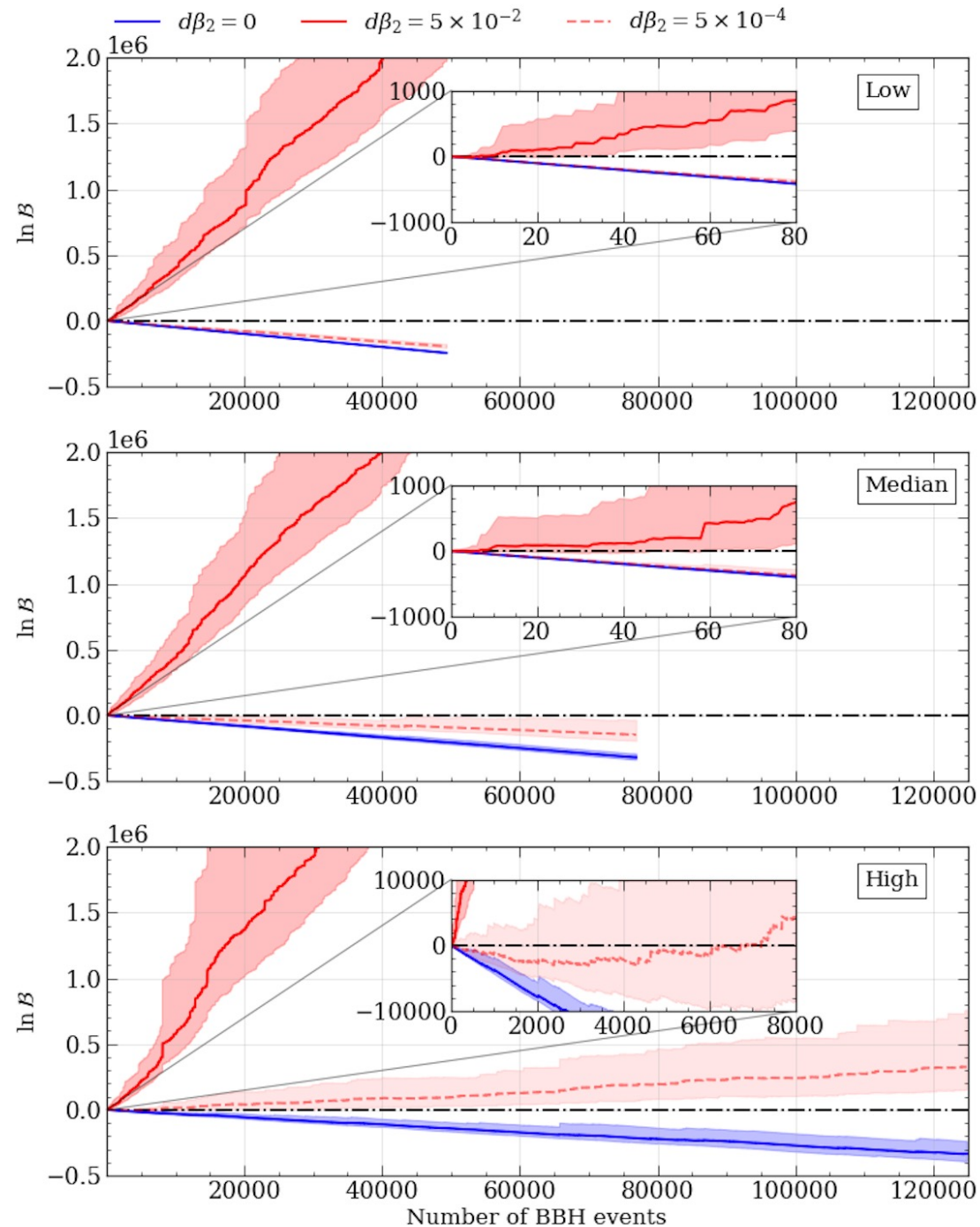
Catalog tests II

Multiplying Bayes factors

- Gaussian posterior. Calculate Bayes factor and multiply BF of multiple events

$$Z_{\text{nonGR}} \equiv \int d\lambda \mathcal{L}(\lambda) \quad \mathcal{B} \equiv \frac{\prod Z_{\text{nonGR}}}{A Z_{\text{GR}}} \rightarrow \log B \sim a \mu^2 + b$$
$$Z_{\text{GR}} \equiv \int d\theta \mathcal{L}_{\text{GR}}(\theta)$$

- Much faster towards a false deviation, for systematic error appears as quadratic term
- Waveform systematics would deteriorate with the increase of overlap rates (more inaccurate subtractions)

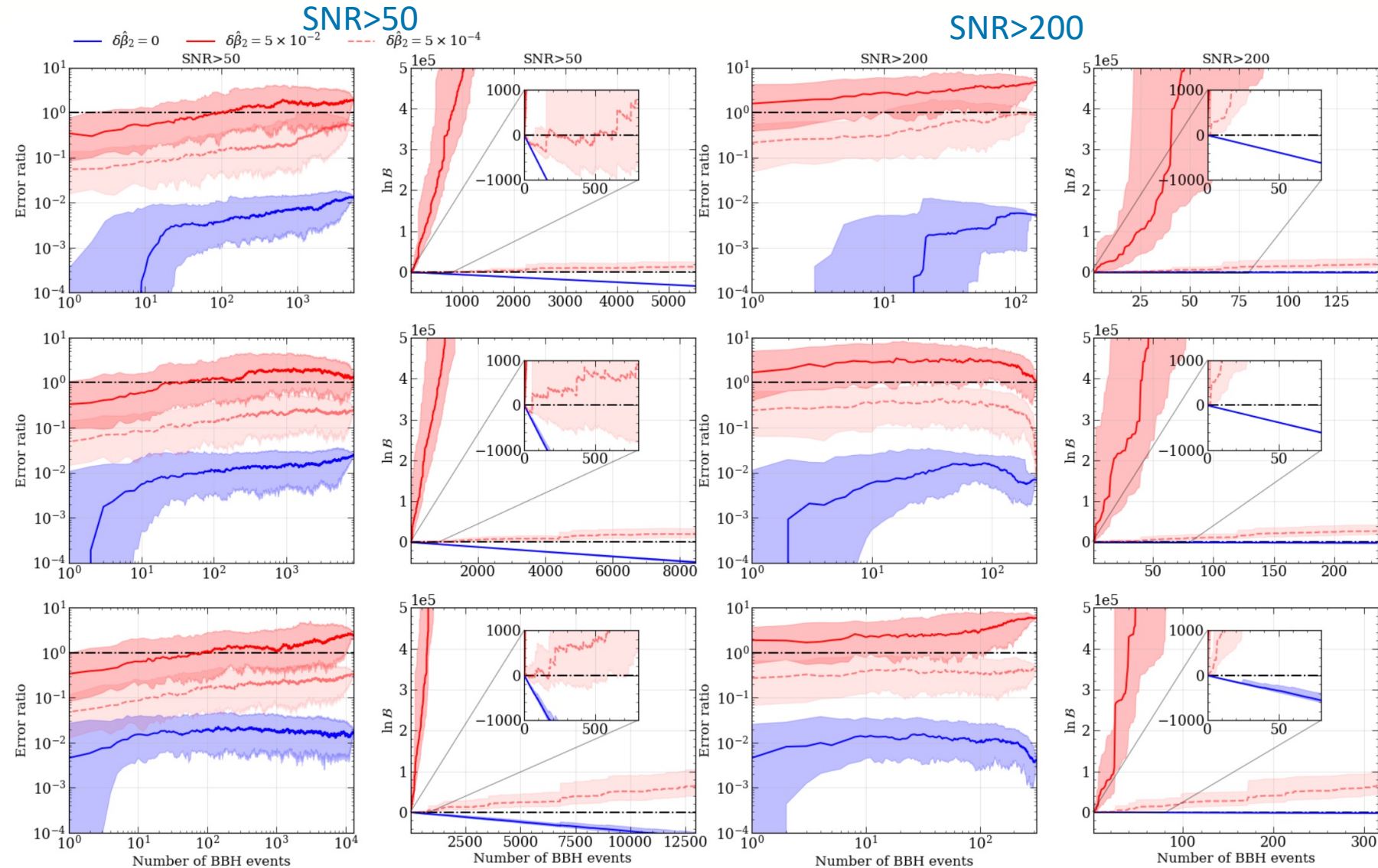


Golden events



Testing GR with selected high SNR and clean events

- SNR>50 or 200 & No detected overlapping signal
- No qualitative difference between different merger rates – as expected
- **More vulnerable to systematic errors!**



Summary



- Waveform systematic vs (detected/undetected) overlap signals:
 - Detected overlapping signals magnifies waveform systematics errors
 - Overlapping signals do not always exist, it is inaccurate waveform that keeps contributing to systematic error
 - Undetected overlaps are more frequent than the detected! Confusion background
- Catalog tests of GR:
 - Systematic errors do accumulate when we combine results from multiple events
 - Multiplying posteriors and BFs could both lead to false deviations. The latter is more sensitive
 - Golden events are more vulnerable to false deviations: systematic error dominates at high SNR scenario
- The idea of error accumulation is universal: testing GR, cosmology, population inference, EoS of neutron stars, ...